

Expand Your Boundaries

Discover the Nano-World with the Hitachi AFM5300E

Vacuum System

- High-resolution observation of electromagnetic properties
- High temperature and cryogenic measurements

In-situ Observation

- In air or in solution
- Humidity control
- Temperature control

Air Protection

- SEM and ion milling compatible sample holder

Environmental-Control Atomic Force Microscope

AFM5300E



Inspire Innovation through Collaboration